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Sheet 1 of 1



FORM PTO-1449 (SUBSTITUTE)

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

INFORMATION DISCLOSURE
STATEMENT BY APPLICANT
(37 CFR 1.98(b))

Attorney Docket No.:
EHF 2001,0167 P

Applic. No.
09/873,230

Applicant

Norbert Benesch et al.

Filing Date
June 4, 2001

Group Art Unit
2621

U.S. PATENT DOCUMENTS

EXAMINER INITIALS		PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE
	A						
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Technology Center 2600

FOREIGN PATENT DOCUMENT

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRANSL. YES NO
JS	J	61 169 750	07/31/86	Japan			X
JS	K	62 200 251	09/03/87	Japan			X
JS	L	9 191 032	07/22/97	Japan			X
JS	M	9 318 330	12/12/97	Japan			X
	N						

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

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FOREIGN PATENT DOCUMENT

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRANSL. YES NO
JS	J	60 224 041	11/08/85	Japan			X
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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

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EXAMINER

John Hrege

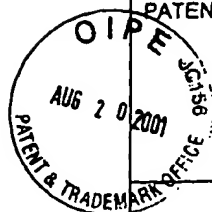
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				Filing Date June 4, 2001			
U.S. PATENT DOCUMENTS							
EXAMINER INITIALS		PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE
JS	A	4,964,726	10/23/90	Kleinknecht et al.	_____	_____	_____
JS	B	5,703,692	12/30/97	McNeil et al.	_____	_____	_____
JS	C	5,830,611	11/03/98	Bishop et al.	_____	_____	_____
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FOREIGN PATENT DOCUMENT							
		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRANSL. YES NO
JS	J	198 24 624 A1	02/25/99	Germany	_____	_____	_____ X
JS	K	0 874 396 A2	10/28/98	Europe	_____	_____	X _____
	L						
	M						
	N						
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)							
JS	O	Scott Bushman et al.: "Scatterometry Measurements for Process Monitoring of Polysilicon Gate Etch", SPIE, vol. 32131997, pp. 79-90, XP-000890146					
JS	P	Stephen A. Coulombe et al.: "Ellipsometric-Scatterometry for sub-0.1 μ m CD measurements", SPIE, vol. 3332, 1998, pp. 282-293, XP-000890148					
EXAMINER John Stapp				DATE CONSIDERED 6/16/04			
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INFORMATION DISCLOSURE STATEMENT BY APPLICANT (37 CFR 1.98(b))	Filing Date June 4, 2001	Group Art Unit

U.S. PATENT DOCUMENTS

EXAMINER INITIALS		PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE
JS	A	5,768,192	06/16/98	Eitan			
JS	B	6,011,725	01/04/00	Eitan			
JS	C	6,191,459 B1	02/20/01	Hofmann et al.			
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FOREIGN PATENT DOCUMENT

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRANSL. YES	NO
	J	196 00 422 C1	08/21/97	Germany				X
	K	196 03 810 C1	08/28/97	Germany				X
	L	195 45 903 A1	06/12/97	Germany				X
	M	196 00 423 A1	07/17/97	Germany				X
JS	N	WO 99/60631	11/25/99	WIPO			X	

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

JS	O	Junko Tanaka et al.: "A Sub-0.1- μ m Grooved Gate MOSFET with High Immunity to Short-Channel Effects", IEDM 93, pp. 537-540;
JS	P	Ken-ichiro Nakagawa et al.: "A Flash EEPROM Cell with Self-Aligned Trench Transistor & Isolation Structure", 2000 Symposium on VLSI Technology Digest of Technical Papers

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